

**Notice of References Cited**Application/Control No.  
**09/607,912**Applicant(s)/Patent Under Reexam  
**Duschatko et al.**Examiner  
**Man Phan**Art Unit  
**2665**

Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	5,717,693	2/1998	Baydar et al.	370	514
B	6,262,975	7/2001	Derbenwick et al.	370	244
C	6,452,906	9/2002	Afferton et al.	370	242
D	5,265,096	11/1993	Parruck	370	216
E	5,442,620	8/1995	Kremer	370	224
F	6,324,162	11/2001	Chaudhuri	370	225
G	6,122,249	9/2000	Mochizuki et al.	370	220
H	6,301,254	10/2001	Chan et al.	370	397
I	6,608,844	8/2003	Teodorescu et al.	370	512
J	6,147,968	11/2000	De Moer et al.	370	225
K	6,298,038	10/2001	Martin et al.	370	216
L	6,421,323	7/2002	Nelson et al.	370	249
M					

**FOREIGN PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
N						
O						
P						
Q						
R						
S						
T						

**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	
V	
W	
X	

<sup>1</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.